HITFET®BTS 933

Smart Lowside Power Switch

Features

- Logic Level Input
- Input Protection (ESD)
- Thermal Shutdown
- Overload protection
- Short circuit protection
- Overvoltage protection
- Current limitation
- Maximum current adjustable with external resistor
- Current sense
- Status feedback with external input resistor
- Analog driving possible

Application

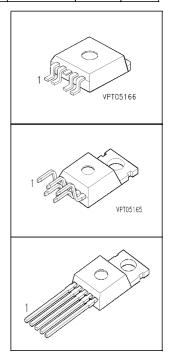
- All kinds of resistive, inductive and capacitive loads in switching or linear applications
- μC compatible power switch for 12 V and 24 V DC applications
- Replaces electromechanical relays and discrete circuits

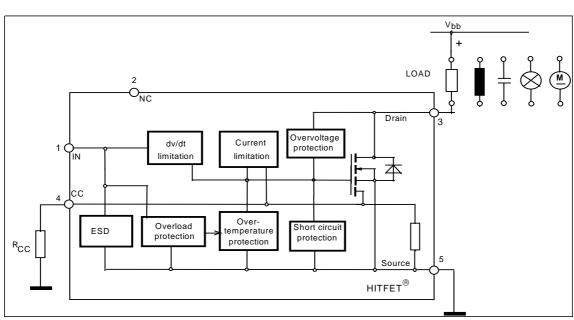
General Description

N channel vertical power FET in Smart SIPMOS $^{\circledR}$ chip on chip technology. Fully protected by embedded protected functions.

Product Summary

Drain source voltage	V _{DS}	60	V
On-state resistance	R _{DS(on)}	50	mΩ
Current limit	I _{D(lim)}	3	Α
Nominal load current	I _{D(ISO)}	7	Α
Clamping energy	E _{AS}	2000	mJ





Maximum Ratings at Tj = 25 °C unless otherwise specified

Parameter	Symbol	Value	Unit
Drain source voltage	V _{DS}	60	V
Drain source voltage for short circuit protection	V _{DS(SC)}		
$R_{\rm CC} = 0 \ \Omega$		15	
without R _{CC}		50	
Continuous input current 1)	I _{IN}		mA
$-0.2V \le V_{IN} \le 10V$		no limit	
$V_{\rm IN}$ < -0.2V or $V_{\rm IN}$ > 10V		<i>I</i> _{IN} ≤ 2	
Operating temperature	T _j	- 40 +150	°C
Storage temperature	$T_{\rm stg}$	- 55 +150	
Power dissipation	P _{tot}	90	W
$T_{\rm C}$ = 25 °C			
Unclamped single pulse inductive energy	E _{AS}	2000	mJ
$I_{D(ISO)} = 7 A$			
Electrostatic discharge voltage (Human Body Model)	V _{ESD}	3000	V
according to MIL STD 883D, method 3015.7 and			
EOS/ESD assn. standard S5.1 - 1993			
Load dump protection $V_{\text{LoadDump}^2} = V_{\text{A}} + V_{\text{S}}$	V_{LD}		
$V_{\rm IN}$ =low or high; $V_{\rm A}$ =13.5 V			
$t_d = 400 \text{ ms}, R_I = 2 \Omega, I_D = 0.5*7A$		90	
$t_d = 400 \text{ ms}, R_I = 2 \Omega, I_D = 7A$		74	
DIN humidity category, DIN 40 040		E	
IEC climatic category; DIN IEC 68-1		40/150/56	

Thermal resistance

junction - case:	R _{thJC}	1.4	K/W
junction - ambient:	R_{thJA}	75	
SMD version, device on PCB: 3)	R_{thJA}	45	

 $^{^{1}}$ A sensor holding current of 500 μ A has to be guaranted in the case of thermal shutdown (see also page 3)

 $^{^2}V_{\mbox{Loaddump}}$ is setup without the DUT connected to the generator per ISO 7637-1 and DIN 40839

³Device on 50mm*50mm*1.5mm epoxy PCB FR4 with 6cm ² (one layer, 70 μm thick) copper area for Drain connection. PCB is vertical without blown air.

Electrical Characteristics Unit **Symbol Values Parameter** at T_i=25°C, unless otherwise specified min. typ. max. **Characteristics** ٧ Drain source clamp voltage 73 60 $V_{\rm DS(AZ)}$ T_i = - 40 ...+ 150°C, I_D = 10 mA Off state drain current 10 μΑ $I_{\rm DSS}$ $V_{DS} = 32 \text{ V}, \ T_i = -40...+150 \text{ °C}, \ V_{IN} = 0 \text{ V}$ ٧ Input threshold voltage 1.3 1.7 2.2 $V_{\rm IN(th)}$ $I_{\rm D} = 1.4 \, \rm mA$ 30 55 μΑ Input current - normal operation, $I_D < I_{D(lim)}$: /IN(1) $V_{1N} = 10 \text{ V}$ Input current - current limitation mode, $I_D=I_{D(lim)}$: 60 150 350 $I_{IN(2)}$ $V_{1N} = 10 \text{ V}$ 1000 2500 4000 Input current - after thermal shutdown, $I_D=0$ A: $I_{IN(3)}$ $V_{IN} = 10 \text{ V}$ Input holding current after thermal shutdown I_{IN(H)} $T_i = 25 \, ^{\circ}\text{C}$ 500 $T_{\rm i} = 150 \, {\rm ^{\circ}C}$ 300 On-state resistance $\mathsf{m}\Omega$ $R_{\rm DS(on)}$ $I_D = 7 \text{ A}, V_{IN} = 5 \text{ V}, T_i = 25 \text{ °C}$ 50 60 $I_D = 7 \text{ A}, V_{IN} = 5 \text{ V}, T_i = 150 \text{ }^{\circ}\text{C}$ 90 120 On-state resistance $R_{\rm DS(on)}$ $I_D = 7 \text{ A}, V_{IN} = 10 \text{ V}, T_i = 25 \text{ °C}$ 40 50 $I_{\rm D} = 7 \text{ A}, \ V_{\rm IN} = 10 \ , \ T_{\rm i} = 150$ 75 100 Nominal load current (ISO 10483) Α 7 $I_{D(ISO)}$

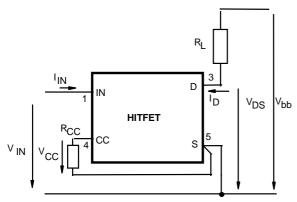
 $V_{IN} = 10 \text{ V}, V_{DS} = 0.5 \text{ V}, T_{C} = 85 \text{ }^{\circ}\text{C}$

Electrical Characteristics		Ι			
Parameter	Symbol	Values			Unit
at T _j =25°C, unless otherwise specified		min.	typ.	max.	
Characteristics					
Initial peak short circuit current limit	I _{D(SCp)}	-	125	-	Α
$V_{IN} = 10 \text{ V}, \ V_{DS} = 12 \text{ V}$					
Current limit 1)	I _{D(lim)}				
$V_{\text{IN}} = 10 \text{ V}, \ V_{\text{DS}} = 12 \text{ V}, \ t_{\text{m}} = 350 \ \mu\text{s},$, ,				
$T_{\rm j}$ = -40+150 °C, without $R_{\rm CC}$		3	7	12	
$V_{\text{IN}} = 10 \text{ V}, \ V_{\text{DS}} = 12 \text{ V}, \ t_{\text{m}} = 350 \ \mu\text{s},$					
$T_{\rm j} = -40+150~{\rm ^{\circ}C},~R_{\rm CC} = 0~\Omega$		60	80	100	
Dynamic Characteristics				•	
Turn-on time V_{IN} to 90% I_{D} :	t _{on}	-	40	100	μs
$R_{L} = -\Omega$, $V_{IN} = 0$ to 10 V, $V_{bb} = 12$ V					
Turn-off time V_{IN} to 10% I_{D} :	t _{off}	-	70	170	μs
$R_{L} = -\Omega$, $V_{IN} = 10 \text{ to } 0 \text{ V}$, $V_{bb} = 12 \text{ V}$					
Slew rate on 70 to 50% V _{bb} :	-dV _{DS} /dt _{on}	-	1	3	V/µs
$R_{L} = -\Omega$, $V_{IN} = 0$ to 10 V, $V_{bb} = 12$ V					
Slew rate off 50 to 70% V _{bb} :	dV _{DS} /dt _{off}	-	1	3	
$R_{L} = -\Omega$, $V_{IN} = 10 \text{ to } 0 \text{ V}$, $V_{bb} = 12 \text{ V}$					
Protection Functions					
Thermal overload trip temperature	$T_{\rm jt}$	150	165	-	°C
Unclamped single pulse inductive energy	E _{AS}				mJ
$I_{D} = 7 \text{ A}, \ T_{j} = 25 \text{ °C}, \ V_{bb} = 32 \text{ V}$		2000	-	-	
$I_D = 7 \text{ A}, T_j = 150 \text{ °C}, V_{bb} = 32 \text{ V}$		450	-		
Inverse Diode					
Inverse diode forward voltage	V_{SD}	-	1.08	-	V
$I_{F} = 5*7A$, $t_{m} = 300 \mu S$, $V_{IN} = 0 V$					

¹Device switched on into existing short circuit (see diagram Determination of $I_{D(lim)}$). Dependant on the application, these values might be exceeded for max. 50 μ s in case of short circuit occurs while the device is on condition

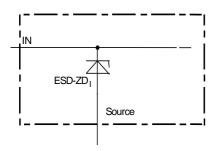
Block Diagramm

Terms



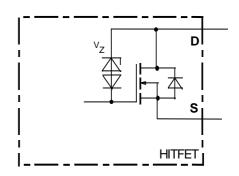
The ground lead impedance of R_{CC} should be as low as possible

Input circuit (ESD protection)

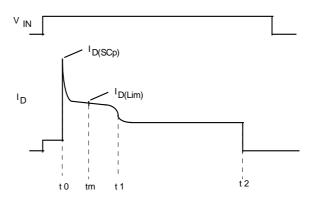


ESD zener diodes are not designed for DC current > 2 mA @ V_{IN} >10V.

Inductive and overvoltage output clamp



Short circuit behaviour



t₀: Turn on into a short circuit

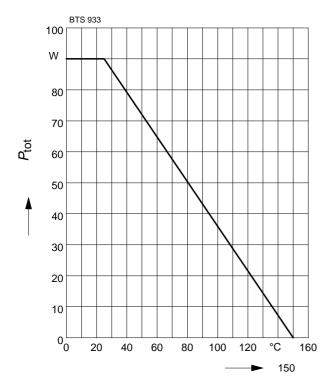
t_m: Measurementpoint for I_{D(lim)}

t₁: Activation of the fast temperature sensor and regulation of the drain current to a level where the junction temperature remains constant.

t₂: Thermal shutdown caused by the second temperature sensor, achieved by an integrating measurement.

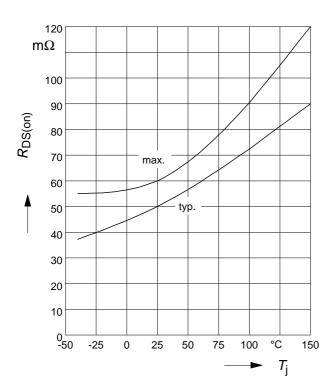
Maximum allowable power dissipation





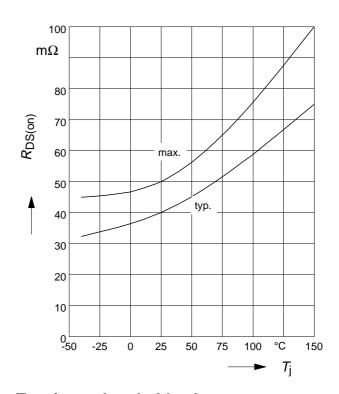
On-state resistance

$$R_{ON} = f(T_i); I_D = 7A; V_{IN} = 5V$$



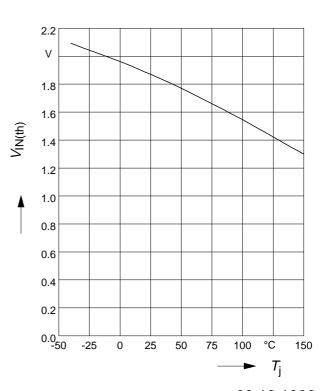
On-state resistance

$$R_{ON} = f(T_i); I_D = 7A; V_{IN} = 10V$$



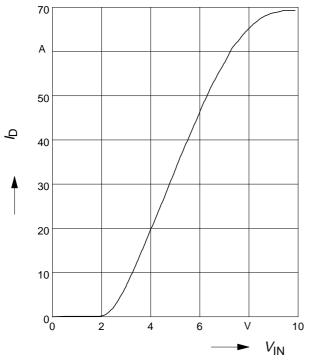
Typ. input threshold voltage

$$V_{IN(th)} = f(T_j); I_D=1,4A; V_{DS}=12V$$



Typ. transfer characteristics

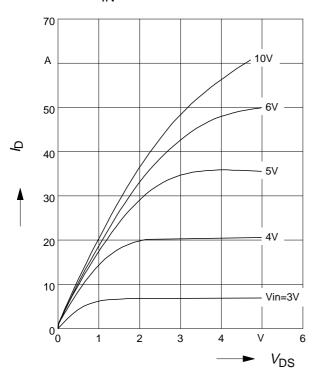
 $I_D = f(V_{IN}); V_{DS}=12V; T_j=25$ °C



Typ. output characteristic

 $I_D = f(V_{DS}); T_j=25$ °C

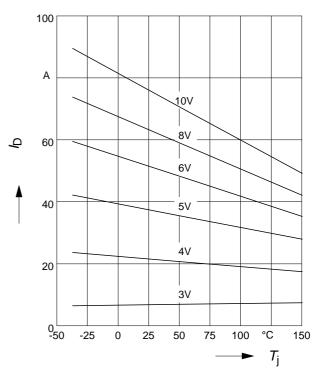
Parameter: V_{IN}



Typ. short circuit current

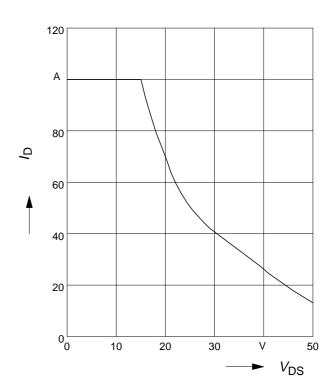
 I_{Dlim} = f(Tj); R_{CC} =0 Ω , V_{DS} =12V

Parameter: V_{IN}



Safe Operating Area

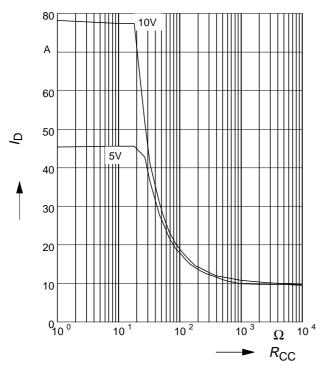
 $I_{D(SC)} = f(V_{DS}); T_j = 25^{\circ}C$



Typ. current limit versus R_{CC}

 $I_{D(lim)} = f(R_{CC}); T_j=25^{\circ}C$

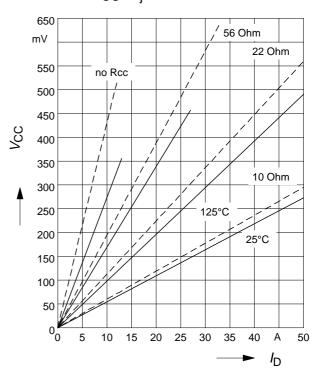
Parameter: V_{IN}



Typ. current sense characteristics

 $V_{CC} = f(I_D); V_{IN}=10V$

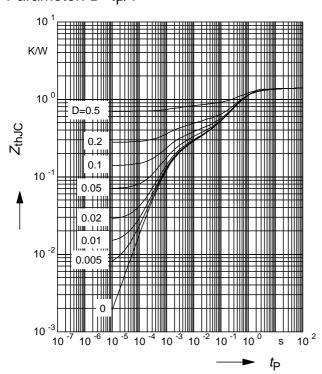
Parameter: R_{CC}, T_i



Transient thermal impedance

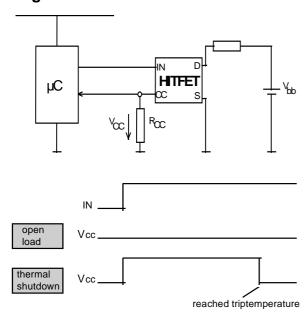
 $Z_{thJC} = f(t_P)$

Parameter: D=tp/T



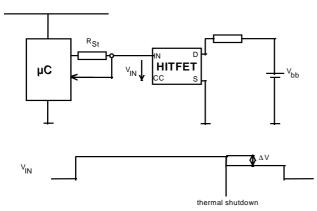
Application examples:

Current Sense Features and Status Signals



The accuray of Vcc is at each temperature about ±10 %

Status signal of thermal shutdown by monitoring input current

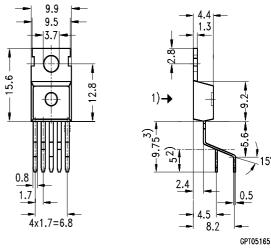


$$\Delta V = R_{ST} * I_{IN(3)}$$

Package and ordering code all dimensions in mm

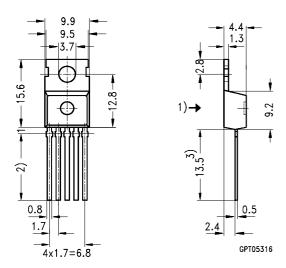
Ordering code: Q67060-S6701-A4

1.3 0.5 0.8 4x1.7 = 6.8GPT05904 Ordering Code: Q67060-S6701-A2



- 1) shear and punch direction no burrs this surface
- 2) min. length by tinning
- 3) max. 11 mm allowable by tinning

Ordering Code: Q67060-S6701-A3



- 1) punch direction, burr max. 0.04
- 2) dip tinning
- 3) max. 14.5 by dip tinning press burr max. 0.05

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